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APPLICATION NO.	FILING DATE	FIRST NAMED INVENTOR	ATTORNEY DOCKET NO.	CONFIRMATION NO.
09/637,570	08/14/2000	Seiichi Kondo	NIT-215	8469
24956	7590 10/29/2003		EXAM	IINER
MATTINGLY, STANGER & MALUR, P.C.			NGUYEN, HA T	
1800 DIAGON	NAL ROAD			
SUITE 370		ART UNIT	PAPER NUMBER	
ALEXANDRI	A. VA 22314		2812	

DATE MAILED: 10/29/2003

Please find below and/or attached an Office communication concerning this application or proceeding.

	Application No.	Applicant(s)				
Office Action Comment	09/637,570	KONDO ET AL.				
Office Action Summary	Examiner	Art Unit				
	Ha T. Nguyen	2812				
The MAILING DATE of this communication ap Period for Reply	ppears on the cover sheet with the	correspondence address				
A SHORTENED STATUTORY PERIOD FOR REPI THE MAILING DATE OF THIS COMMUNICATION. Extensions of time may be available under the provisions of 37 CFR 1. after SIX (8) MONTH'S from the mailing date of this communication. If NO period for reply is specified above, the maximum statutory period. Failure to reply within the set or extended period for reply will, by shatur. Any reply received by the Office later than three months after the mailing amend patent term adjustment. See 37 CFR 1 704(b). Status	.135(a). In no event, however, may a reply be to ply within the statutory minimum of thirty (30) da st will apply and will expire SIX (6) MONTHS for to, cause the application to become ABANDON	imely filed sys will be considered timely, in the mailing date of this communication. ED (35 U.S.C. § 133).				
1) Responsive to communication(s) filed on 03	September 2003 .					
2a)⊠ This action is FINAL . 2b)□ T	his action is non-final.					
3) Since this application is in condition for allowance except for formal matters, prosecution as to the merits is						
closed in accordance with the practice under Disposition of Claims	r Ex parte Quayle, 1935 C.D. 11,	453 O.G. 213.				
4)⊠ Claim(s) <u>1-21</u> is/are pending in the application.						
4a) Of the above claim(s) is/are withdrawn from consideration.						
5) Claim(s) is/are allowed.						
6)⊠ Claim(s) <u>1-21</u> is/are rejected.						
7) Claim(s) is/are objected to.						
Claim(s) are subject to restriction and/or election requirement. Application Papers						
9) The specification is objected to by the Examin-	er.					
10)☐ The drawing(s) filed on is/are: a)☐ accepted or b)☐ objected to by the Examiner.						
Applicant may not request that any objection to the drawing(s) be held in abeyance. See 37 CFR 1.85(a).						
11) The proposed drawing correction filed on is: a) approved b) disapproved by the Examiner.						
If approved, corrected drawings are required in reply to this Office action.						
12) The oath or declaration is objected to by the Examiner.						
Priority under 35 U.S.C. §§ 119 and 120						
13) Acknowledgment is made of a claim for foreign	gn priority under 35 U.S.C. § 119	(a)-(d) or (f).				
a) All b) Some * c) None of:						
 Certified copies of the priority document 	nts have been received.					
Certified copies of the priority document	nts have been received in Applica	tion No				
Copies of the certified copies of the pricapplication from the International B See the attached detailed Office action for a lis	ureau (PCT Rule 17.2(a)).	•				
14) Acknowledgment is made of a claim for domestic priority under 35 U.S.C. § 119(e) (to a provisional application).						
 a) ☐ The translation of the foreign language pr 15) ☐ Acknowledgment is made of a claim for domes 						
Attachment(s)						

1) Notice of References Cited (PTO-892)
2) Notice of Draftsperson's Patent Drawing Review (PTO-948)
3) Information Disclosure Statement(s) (PTO-1449) Paper No(s)

Interview Summary (PTO-413) Paper No(s).
 Notice of Informal Patent Application (PTO-152)
 Other:

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DETAILED ACTION

Notice to applicant

 Applicants' Amendment and Response to the Office Action mailed 5-26-3 has been entered and made of record (Paper No. 0903).

Response to Amendment

 In view of Applicants' arguments and the amendment to the claims, the objection to claims 1-5, 9, 10, 13, 16, 19, and 20, the rejection of claims 7 and 8 under 35 U.S.C. 112, second paragraph, and the rejections of claims 1-21 under 35 U.S.C. 103, as stated in Paper No. 20, have been withdrawn.

Applicants' arguments with regard to the rejections under 35 U.S.C. 103 have been fully considered, but they are not deemed to be persuasive. The response to these arguments will be incorporated in the new ground of rejection given below. Note that Applicants' argument regarding the effect of the surfactant on the polishing rate is irrelevant since none of the claims recite this limitation.

Claim Rejections - 35 USC § 103

- The following is a quotation of 35 U.S.C. 103(a) which forms the basis for all
 obviousness rejections set forth in this Office action:
 - (a) A patent may not be obtained though the invention is not identically disclosed or described as set forth in section 102 of this title, if the differences between the subject matter sought to be patented and the prior art are such that the subject matter as a whole would have been obvious at the time the invention was made to a person having ordinary skill in the art to which said subject matter pertains. Patentability shall not be negatived by the manner in which the invention was made.

This application currently names joint inventors. In considering patentability of the claims under 35 U.S.C. 103(a), the examiner presumes that the subject matter of the various claims was commonly owned at the time any inventions covered therein were made absent any evidence to the contrary. Applicant is advised of the obligation under 37 CFR 1.56 to point out the inventor and invention dates of each claim that was not commonly owned at the time a later invention was made in order for the examiner to consider the applicability of 35 U.S.C. 103® and potential 35 U.S.C. 102(f) or (g) prior art under 35 U.S.C. 103(a).

 Claims 1-21 are rejected under 35 U.S.C. 103(a) as being unpatentable over Kaufman in view of Sun and Costas et al. (USPN 6607424, hereinafter "Costas") or Yoshida et al. (USPN 6221118, hereinafter "Yoshida").

[Claims 1-3] Kaufman discloses a polishing method by chemical mechanical polishing for a copper film formed on an insulating layer including via holes using a polishing liquid containing an oxidizing substance, a phosphoric acid, and a protection-layer forming agent and a surfactant; wherein said oxidizing substance contains hydrogen peroxide, and said phosphoric acid contains one selected from the group of orthophosphoric acid and phosphorous acid; and wherein said protection-layer forming agent contains benzotriazole (see col. 1, lines 53-67 and col. 4, line 53-col. 6, line 55). Hawley's dictionary is cited to show that in the normal use "phosphoric acid" means "orthophosphoric acid". It is inherent that the forming agent forms a protection-layer and the protection-layer is polished away on a convex portion of the copper film and the oxidizing substance oxidizes a surface of the convex portion of the copper film and renders an oxidized surface water soluble as a Cu ion by phosphoric acid. But it does not disclose expressly that the polishing slurry is substantially free from abrasive, that the surfactant is comprised in the forming agent, and the surfactant having a molecular weight not less than 10000. However, since the surfactant is a part of the Kaufmann's slurry, the resulting effect is the same, as when the surfactant is a part of the forming agent which is also mixed in the slurry, and the abrasive free limitation is well known in the art because Sun discloses this feature (See abstract), Costas discloses a polishing composition containing polyacrylic acid of average molecular weight of about 20000-155000 (see col. 4, lines 8-17) or Yoshida discloses surfactant of ammonium polyacrylate having average molecular weight of about 5000-20000 (see col. 2, line 54- col. 3, line 16), note that polyacrylic acid and ammonium polyacrylate are also polymeric thickener and protection-layer forming agent. A person of ordinary skill is motivated to modify Kaufman with Sun and Costas or Yoshida to obtain scratch free planar surface using effective composition.

[Claims 9, 10, 13-15, 19, and 20] An argument similar to the rejection of claims 1-3 applies. Kaufman also discloses a polishing method comprising (a)depositing a first metal film of a barrier metal on an insulating film having convex and concave portions, depositing a second

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metal film of copper on the first metal film (See abstract and col. 1, lines 40-65); (b) removing the second metal film on the convex portion and leaving the second metal film in the concave portion on the first metal by chemical mechanical using a polishing liquid containing an oxidizing substance, a phosphoric acid a surfactant, an abrasive and a protection-layer forming agent comprising an anticorrosive, (col. 4, line 53-col. 6, line 55), and (c)removing the first metal film on the convex portion and leaving the first metal in the concave portion by chemical mechanical polishing by a second polishing liquid obtained by adding an abrasive to said first polishing liquid (see col. 7, line 23-col. 9, line 23); and the second polishing liquid contains the protection-layer forming agent in a larger amount than said first polishing liquid (see col. 6, lines 37-42 and col. 8, lines 27-44). But it does not disclose expressly that the first polishing liquid is free of abrasive and the etching of the first metal film is by dry etching. However, the missing limitations are well known in the art because Sun discloses the etching with an abrasive free liquid, as shown above. The combined teaching of Kaufman and Sun does not teach the dry etching of the first metal film and the reducing atmosphere plasma cleaning exposed surface of metal for its adherence to a subsequently formed interconnect. However, the examiner takes Official Notice that these features are well known in the art. A person of ordinary skill is motivated to modify Kaufman with Sun and Costas or Yoshida to reduce dishing.

[Claims 6 and 7] Kaufman discloses a polishing method for removing a copper film over an insulating film including via holes by chemical mechanical polishing, by using a polishing liquid containing an oxidizing substance, a phosphoric acid, benzotriazole (See abstract, col. 1, lines 40-65 and col. 4, line 53-col. 55), it is inherent that benzotriazole forms a protection-layer, the protection-layer is polished away on a convex portion of the copper film, the oxidizing substance oxidizes a surface of the convex portion of the copper film and the phosphoric acid renders an oxidized copper film water soluble. But it does not disclose expressly that the forming agent of the polishing liquid comprising an acrylic acid polymer and is substantially free of abrasives. However, the missing limitations are well known in the art because Sun discloses the use of abrasive free polishing liquid as shown above and Costas or Yoshida discloses the use of an acrylic acid polymer in the polishing liquid, as shown above. A person of ordinary skill is motivated to modify Kaufman with Sun and Costas or Yoshida to reduce dishing (See Sun, abstract).

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[Claims 4, 5, 8, 11, 12, 16-18, and 21] Arguments similar to the rejection of claims 6, 7 and of claims 9, 10, 13-15, 19, and 20 also apply. Kaufman also discloses a polishing method comprising (a)depositing a first metal film of a barrier metal on an insulating film having convex and concave portions, depositing a second metal film of copper on the first metal film (See abstract and col. 1, lines 40-65); (b) removing the second metal film on the convex portion and leaving the second metal film in the concave portion on the first metal by chemical mechanical using a polishing liquid containing an oxidizing substance, a phosphoric acid and a protectionlayer forming agent (col. 4, line 53-col. 55), and (c) removing the first metal film on the convex portion and leaving the first metal in the concave portion by chemical mechanical polishing by a second polishing liquid obtained by adding an abrasive to said first polishing liquid (see col. 7, line 23-col. 9, line 23); and the second polishing liquid contains the protection-layer forming agent in a larger amount than said first polishing liquid (see col. 6, lines 37-42 and col. 8, lines 27-44). But it does not disclose expressly that the first polishing liquid is free of abrasive and that the forming agent of the polishing liquid contains a polymer selected from polyacrylic acid, polyammonium acrylate, polyamine acrylate, or bridged polymer thereof. However, the missing limitations are well known in the art because Sun and Costas or Yoshida discloses these features, as shown above.

Therefore, it would have been obvious to combine Kaufman with Sun and Costas or Yoshida to obtain the invention as specified in claims 1-21.

Conclusion

Applicant's amendment necessitated the new ground(s) of rejection presented in this
Office action. Accordingly, THIS ACTION IS MADE FINAL. See MPEP § 706.07(a).
Applicant is reminded of the extension of time policy as set forth in 37 CFR 1.136(a).

A shortened statutory period for response to this final action is set to expire THREE MONTHS from the date of this action. In the event a first response is filed within TWO MONTHS of the mailing date of this final action and the advisory action is not mailed until after the end of the THREE-MONTH shortened statutory period, then the shortened statutory period will expire on the date the advisory action is mailed, and any extension fee pursuant to 37 CFR 1.136(a) will be calculated from the mailing date of the advisory action. In no event will

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the statutory period for response expire later than SIX MONTHS from the date of this final action.

6. Any inquiry concerning this communication or earlier communications from the examiner should be directed to Ha Nguyen whose telephone number is (703)308-2706. The examiner can normally be reached on Monday-Friday from 8:30AM to 6:00PM, except the first Friday of each bi-week. The phone number for Wednesday is (703) 560-0528.

If attempts to reach the examiner by telephone are unsuccessful, the examiner's supervisor, John Niebling, can be reached on (703) 308-3325. The fax phone number for this Group is (703) 872-9306.

Any inquiry of a general nature or relating to the status of this application or proceeding should be directed to the Group receptionist whose telephone number is (703) 308-0956.

1/

Ha Nguyen Primary Examiner

10-18-03